PATENT APPLICATION

FORM PTO-1449

ATTY. DOCKET NO.

SERIAL NO.

10991002-4

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE **STATEMENT**

APPLICANT

Tetsuya Takeuchi et al.

FILING DATE

GROUP

(Use several sheets if necessary)

Herewith

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER		DATE	NAME	CLASS	SUB CLASS	
pw	AA	5,798,537	08/25/98	Koichi Nitta	257	103	
	AB	5,670,798	09/23/97	Jan F. Schetzina	257	96	
	AC	5,146,465	09/08/92	Muhammad A. Khan et al.	372	45	
	AD	5,592,501	01/07/97	John A. Edmond et al.	372	45	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
DM	AE/	EP0772249A	05/07/97	EP		
	AF /	EP0723303A	07/24/96	EP		
	AG -	EP0678945A	10/25/95	EP		

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

DW	AH /	Amano, H. et al. "Improvement of Crystalline Quality of Group III Mitrides on Sapphire Using Low Temperature Interlayers", MRS Internet J. Nitride Semiconductor Res. 4A1, G10.1, 1999.
	AI_	Nakamura, S. et al., "Continuous-Wave Operation of InGaN/GaN/AlGaN-based Laser Diodes grown on GaN Substrates", Applied Physics Letters, Vol. 72, No. 16, April 20, 1998, pp. 2014-2016.
	AJ Z	Ohba, Y., "Fabrication and Characterization of AlGaN/GaN Double-Heterolaser Structures on Sapphire Substrates Using Single Crystalline AIN Buffer Layers", Japan J. Physics, Vol. 37, 1998, pp.905-906.
	AK ,	Hofstetter, Daniel et al., "Excitation of a Higher Order Transverse Mode in an Optically Pumped 'In _{0.15} Ga _{0.85} N/In _{0.05} Ga _{0.95} N Multiquantum Well Laser Structure", Applied Physics Letters, Vol. 70, No. 13, March 31, 1997, pp. 1650-1652.
	AL	Nakamura, S. et al., "InGaN/GaN/AlGaN-based Laser Diodes with Modulation-Doped Strain-Layer Supelattices Grown on an Epitaxially Laterally Overgrown GaN Substrate", Applied Physics Letters, Vol. 72, No. 2, January 12, 1998, pp. 211-213.
	AM	Ito, K., et al., "Preparation of Al _x Ga _{1-x} N/GaN Heterostructure by MOVPE", Journal of Crystal Growth, Vol. 104, 1990, pp. 533-538.
	AN	
	AO	
	ĄΡ	
EXAMINED	\mathcal{U}	DATE CONSIDERED 04/21/03

Rev 5/90 (Form 3.05)

DATE CONSIDERED

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PATENT APPLICATION

Sheet 1 of 1

	ATTY, DOCKET NO.	SERIAL NO.
FORM PTO-1449	10991002-4	10/040,328
CLIST OF PATENTS AND PUBLICATIONS FOR	APPLICANT	
APPLICANT'S INFORMATION DISCLOSURE	Tetsuya Takeuchi et a	ıl.
MAR 0 4 2002	FILING DATE	GROUP
(Use several sheets if necessary)	Dec. 19, 2001	

TRANSFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME
	1A			
	1B			
	1C			
	1D			
	1E			
	1F			
	1G			
	1H			
	11			
	1J			
	1K			

FOREIGN PATENT DOCUMENTS

		DOCUMENT	DATE	NAME	TRAN	SLATION
		NUMBER		. IVAIVIE	YES	NO
DW	1L	WO 99/25030	05/20/99	PCT		
ow	1M	09-199759	07/31/97	Japan	×	
	퀽					
	10					
	1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

pw	10	Usui, Akira et al., "Thick GaN Epitaxial Growth with Low Dislocation Density by Hydride Vapor Phase Epitaxy", Japan Journal of Applied Physics, Vol. 36, 1997, pp. L899-902.
ŋw	1R	Takahashi, Naoyuki, "Growth of GaN on GaAs (111)B by Mitalorganic Hydrogen Chloride VPE Using Double Buffer Layer", Japan Journal of Applied Physics, Vol. 36, 1997, pp. L1133-1135.
UN	15	Grandjean, N t al., "Si and Mg Doped GaN Layers Grown by Gas Source Molecular Beam Epitar Using Ammonia", Mat. Res. Soc. Symposium, Vol 482, 1998, pp. 211-216.
EXAMIN	IER	DATE CONSIDERED 04/21/03